

FTP05N06N

Lead Free Package and Finish

R_{DS(ON)}(Typ.)

3.1mΩ

G

TO-220

Packages Not to Scale I_{D (Silicon}

limited current)

150A

D

S

N-Channel MOSFET

Applications:

- Adaptor
- Charger
- .SMPS

Features:

- RoHS Compliant
- . Low ON Resistance
- . Low Gate Charge
- Peak Current vs Pulse Width Curve
- Inductive Switching Curves

Ordering Information

PART NUMBER	PACKAGE	BRAND
FTP05N06N	TO-220	IPS

Absolute Maximum Ratings

 $T_C=25^{\circ}C$ unless otherwise specified

Pb

 V_{DSS}

60V

Symbol	Parameter	FTP05N06N	Units
V _{DSS}	Drain-to-Source Voltage	60	V
I _D	Continuous Drain Current	150	А
	Continuous Drain Current $T_c = 100^{\circ}C$	95	А
I _{DM}	Pulsed Drain Current (NOTE *1)	600	А
V _{GS}	Gate-to-Source Voltage	±20	V
E _{AS}	Single Pulse Avalanche Energy(NOTE *2)	1213	mJ
TL	Maximum Temperature for Soldering	300	
$T_{\rm J}$ and $T_{\rm STG}$	Operating Junction and Storage Temperature Range	150,-55 to150	°C

GDS



Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	60			V	V _{GS} =0V, I _D =250µA
I _{DSS}				1	– μΑ	V _{DS} =60V, V _{GS} =0V
	Drain-to-Source Leakage Current					T _a =25℃
	Drain-to-Source Leakage Current			500		V_{DS} =48V, V_{GS} =0V
				500		T _a =125℃
699	Gate-to-Source Forward Leakage			+100	n A	V_{GS} =+20V
	Gate-to-Source Reverse Leakage			-100	nA	V _{GS} = -20V

OFF Characteristics $T_C=25^{\circ}C$ unless otherwise specified

ON Characteristics $T_J=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
R _{DS(ON)}	StaticDrain-to-Source On-Resistance		3.1	4.5	mΩ	V _{GS} =10V, I _D =40A
V _{GS(TH)}	Gate Threshold Voltage	2	3	4	V	$V_{DS}=V_{GS}$, $I_{D}=250\mu$ A
Pulse width s	\leqslant 300µs; duty cycle \leqslant 2%					

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
Rg	Gate Resistance		0.9		Ω	f=1MHz, V _{GS} =0V,
_						V _{DS} =0V
C _{iss}	Input Capacitance		4500			V _{GS} = 0V,V _{DS} = 25V f =1.0MHz
C _{oss}	Output Capacitance		796		pF	
C _{rss}	Reverse Transfer Capacitance		617			
Q _g	Total Gate Charge		109.8			
Q _{gs}	Gate-to-Source Charge		18.3		nC	$I_D=25A, V_{DD}=48V$ $V_{GS}=10V$
Q _{gd}	Gate-to-Drain ("Miller") Charge		49.8			$v_{GS} = 10v$

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
t _{d(ON)}	Turn-on Delay Time		30.3			V_{DD} =40V, I_D =25A, V_G =10V R_G =6 Ω
t _{rise}	Rise Time		33.5			
t _{d(OFF)}	Turn-Off Delay Time		87.2		ns	
t _{fall}	Fall Time		49			



Source-Drain Diode Characteristics	Tc=25 $^{\circ}$ C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
I _S	Continuous Source Current (Body Diode)			150	A	T 25°0
I _{SM}	Maximum Pulsed Current (Body Diode)			600	А	T _C =25℃
V _{SD}	Diode Forward Voltage			1.2	V	I _{SD} =30A, V _{GS} =0V
t _{rr}	Reverse Recovery Time		55.6		ns	I _F =20A
Q _{rr}	Reverse Recovery Charge		83.2		nC	di/dt=100A/us
Pulse width \leq 300µs; duty cycle \leq 2%						

Notes:

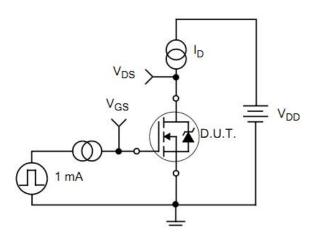
*1. Repetitive rating; pulse width limited by maximum junction temperature.

*2. L=0.5mH, I_D =69.7A, Start T_J =25 $^{\circ}$ C



Test Circuits and Waveforms

Figure 14. Gate Charge Test Circuit



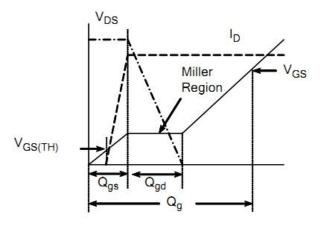
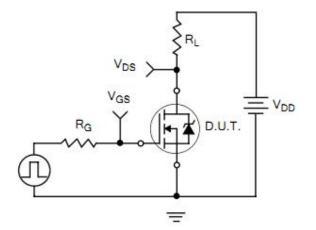
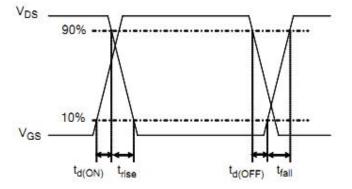


Figure 15. Gate Charge Waveforms

Figure 16. Resistive Switching Test Circuit

Figure 17. Resistive Switching Waveforms







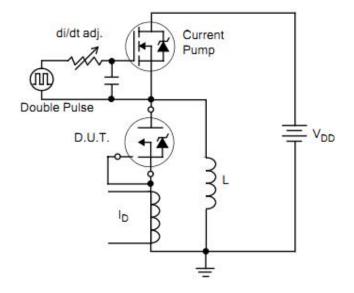


Figure 18. Diode Reverse Recovery Test Circuit

Figure 19. Diode Reverse Recovery Waveform

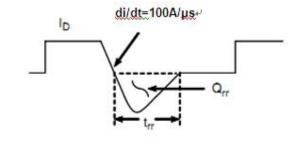
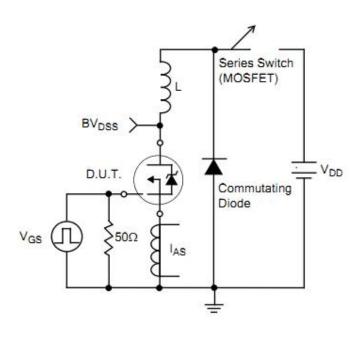
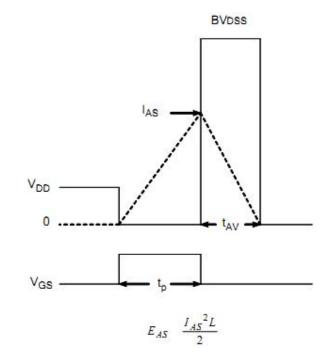


Figure20.Unclamped Inductive Switching Test Circuit

Figure21.Unclamped Inductive Switching Waveform







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